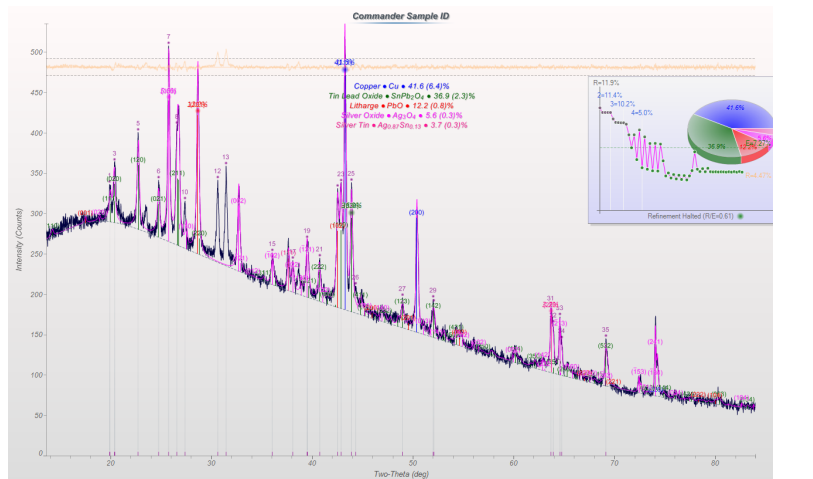
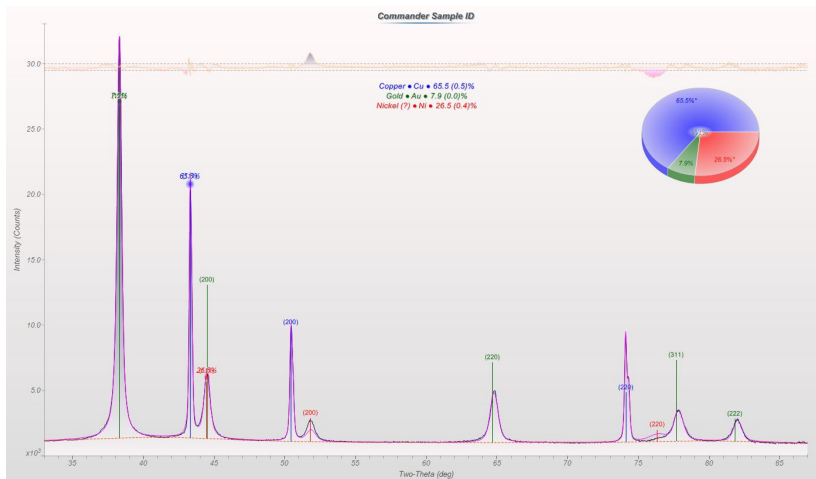
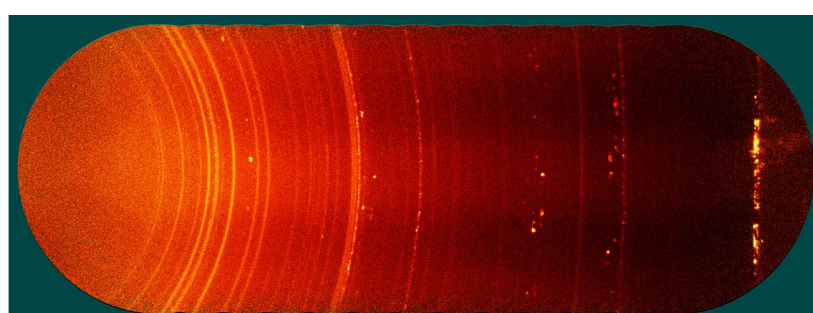
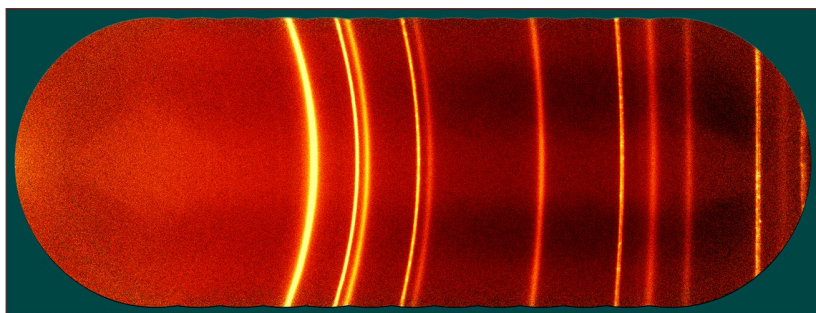
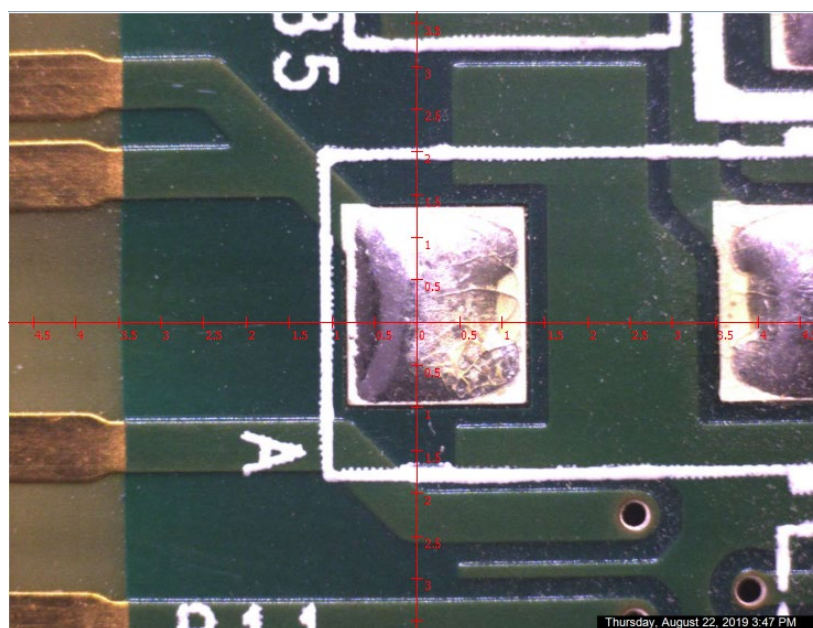
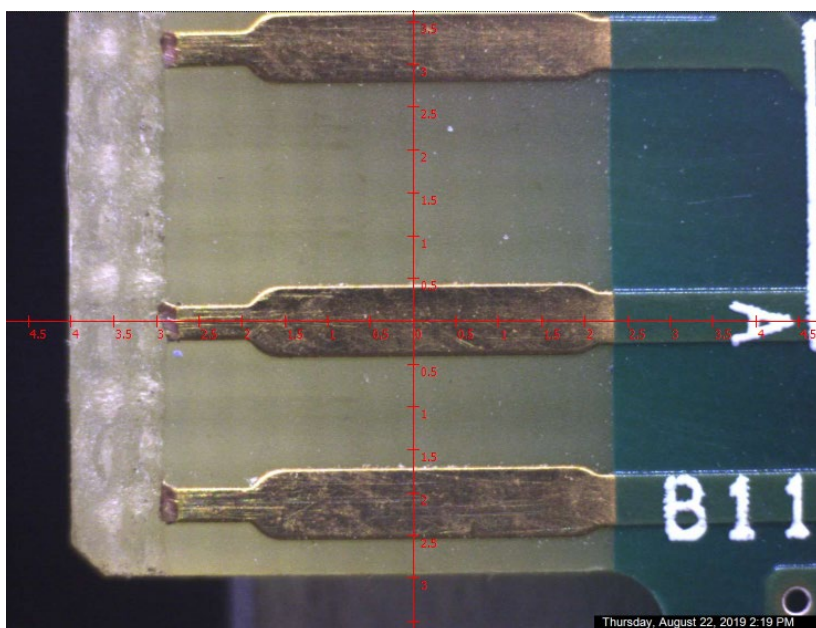


## X-ray diffraction with Bruker D8 GADDS: Compositional analysis circuit board components



Diffraction patterns and analysis from two different sub-millimeter areas of whole circuit board, showing material composition of edge connector (left) and solder (right).

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